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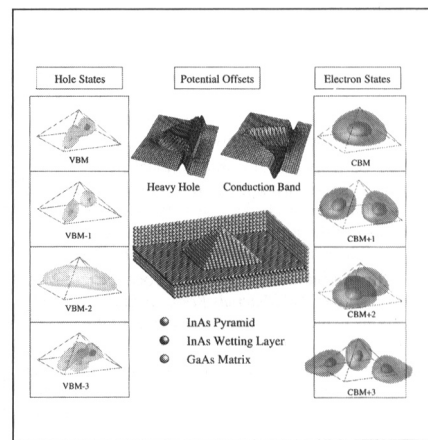
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ON THE COVER: The electronic structure of a 45-Å-high, 90-Å-base, strained InAs pyramidal quantum dot embedded within GaAs. The strain-modified band offsets (for holes and electrons) are shown above the atomic structure. They exhibit a well for both heavy holes and electrons. These are localized within the pyramid and wetting layer as shown by the blue raised (lowered) triangle and ridge (trough), respectively. Isosurface plots of the four highest hole states and four lowest electron states as obtained from pseudopotential calculations appear on the left and right. The lowest electron state—the conduction band minimum (CBM)—is *s*-like, while the next two states (CBM+1 and CBM+2) are nondegenerate *p*-like. From J. Kim, L.W. Wang, A.J. Williamson, and A. Zunger (unpublished). The calculation was performed using the Cray T3E at the National Research Scientific Computing Center at the University of California—Berkeley. See also the article by A. Zunger on page 35 of this issue.

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MRS Bulletin (ISSN: 0883-7694) is published 12 times a year by the Materials Research Society, 506 Keystone Drive, Warrendale, PA 15086-7573. Application to mail at periodicals rates has been approved at Warrendale, PA and at additional mailing offices. POSTMASTER: Send address changes to *MRS Bulletin* in care of the Materials Research Society, at the address listed; phone 412-779-3003; fax 412-779-8313. Printed in the U.S.A.

Additional copies of articles in *MRS Bulletin* may be made at \$2.50 per article. This fee can be paid to the Materials Research Society through the Copyright Clearance Center, Inc., 27 Congress Street, Salem, MA 01970.

Membership in MRS is \$75 annually for regular members, \$25 for students. Dues include an allocation of \$29 (\$17 for students) to a subscription to *MRS Bulletin*. Individual member subscriptions are for personal use only. Non-member subscription rates are \$155 for one calendar year (12 issues) within the U.S.A. and \$215 elsewhere. Single copies may be purchased for \$16 each. Send subscription orders to Subscription Department, Materials Research Society, 506 Keystone Drive, Warrendale, PA 15086-7573.

MRS Bulletin is included in *Current Contents®/Engineering, Computing, and Technology*; *Current Contents®/Physical, Chemical, and Earth Sciences*, the *SciSearch®* online database, *Research Alert®*, *Science Citation Index®*, and the *Materials Science Citation Index™*. Back volumes of *MRS Bulletin* are available in 16 mm microfilm, 35 mm microfilm, or 105 mm microfiche through University Microfilms Inc., 300 North Zeeb Road, Ann Arbor, Michigan 48106.

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